CONFIDENTIAL - INTELLIGENT SOFTWARE & ENTERPRISE COMPUTERS LTD.

Document .... PER-24
Title ...... Enterprise Peripherals Test Report
Issue ...... 1

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The tests outlined below were performed specifically on the following equipment:

Enterprise 128, model 400, serial number LS210 Motherboard issue B, No. 1 RAM card issue B, No. 1 Disk controller issue B, No. 4

Note that the other issue B boards were tried and proven to work. Issue A boards have also been shown to work (with modifications incorporated as in issue B). The only problems experienced were with Enterprises without the additional ground link.

The tests may be grouped into three types:

- 1) Logical function (ie. that the boards logically conform to the specification).
- 2) Timing (ie. that the boards meet the timing requirements of the Enterprise, as specified in the appropriate document).
- 3) Noise and other problems not included in (1) and (2) above.

Summary of test stages 1 - 3:

1) The logical functioning of the three boards has been established through use in developing the disk software and frequent general usage of disk and network systems at I.S.

Those signals supplied by the motherboard but not used by current peripherals were checked. The RAM on the RAM card was tested by running the modified hot soak test. Additionally, a small program (listed below) was executed from segment 30H (a RAM card in a motherboard) to prove Ml cycles without wait states functioned correctly, since this is the most time-critical cycle.

DI ; Disable interrupts LD A,8 OUT (OBFH), A ; Turn off RAM Ml waits LOOP INC A OUT (81H), A ; Flash border continuously JR LOOP

The ROM socket on the RAM card was tested by running BASIC from The disk controller has been checked extensively during disk software development/testing.

Additionally, all the pen-plots were checked against circuit diagrams. Finally, it was proven that it was possible to use six RAM cards, or five RAM cards plus a disk controller, motherboard and that this configuration worked as expected.

- 2) The timing was checked on the early prototypes, and provided that all components are within specification, worst-case calculated timings will be met, with one exception: with a RAM card running in a motherboard, the data setup (REF. 11, document PER-6) on a RAM read cycle is lns too short without waits in theory, but easily meets the requirement in practice (see document PER-17). See also test result in section (1) above.
- 3) Noise was checked on the motherboard by inserting cards in various slots and measuring ground noise and ringing on the bus (eg. /MREQ, /RD, data and address busses), which were found to be within tolerable levels (ie. below VIL max. when signal is required to be valid). Test results are listed on the following pages.

Power was connected and disconnected to the computer and motherboard numerous times with a disk in a connected drive without causing any corruption of disk data. This problem appears to be solved (although users should be warned not to try this!).

No other problems showed up during testing or in normal use.

## Motherboard noise/ringing measurement test results.

Measurements were made using a 50MHz Hitachi V-509 oscilloscope. Ground (b20), /RD (a3), /WR (b2), /MREQ (a5), A0 (a10), A8 (a6), D0 (a14) and D7 (b17) were monitored at two points on the bus (at slot 1 and slot 6). The highest positive and negative noise peaks on the ground rail, and the highest positive and negative ringing peaks after a high-to-low transition on signals were recorded. Ringing was at a frequency of approximately 40-60MHz. Other signals were checked at random and found to be similar. All voltages are relative to ground, pin b20, on the computer expansion port. Noise pickup on the 'scope probe connected to it's own ground was about 400mV pk-pk. The measurements were performed under four load conditions, outlined below, while running the modified hot soak. A lab PSU provided the 5V supply.

- i) Disk controller in slot 1 (testing segment FC).
- ii) RAM card in slot 1 (testing segment 30).
- iii) RAM card in slot 6 (testing segment D0).
  iv) RAM cards in slots 1 to 6 (testing segment 90).

Signal	Measuring point	Load (i) +ve pk -ve pk (mV)		Load (ii) +ve pk -ve pk (mV)	
Ground	Slot 1	350	-400	350	-400
	Slot 6	450	-500	350	-400
/RD	Slot 1	750	-400	700	-400
	Slot 6	750	-450	700	-500
/WR	Slot 1	700	-200	600	-100
	Slot 6	700	-300	650	-200
/MR EQ	Slot 1	700	-100	650	-100
	Slot 6	75 0	-250	700	-300
AO	Slot 1	700	-5 0 0	650	-300
	Slot 6	700	-400	800	-450
A8	Slot 1	700	-200	750	-350
	Slot 6	750	-400	75 0	-450
D0	Slot 1	n/a	n/a	700	-300
	Slot 6	n/a	n/a	700	-200
D7	Slot 1	n/a	n/a	650	-100
	Slot 6	n/a	n/a	700	-150

Signal	Measuring point	+ve pk	(iii) -ve pk (mV) +		d (iv) -ve pk (mV)
Ground	Slot 1		-350	300	-400
	Slot 6	300	-400	250	-400
/RD	Slot 1	700	-450	75 0	-600
	Slot 6	750	-650	800	-900
/WR	Slot 1	700	-250	700	-500
	Slot 6	700	-500	75 0	-750
/MR EQ	Slot 1	650	-450	650	-400
	Slot 6	750	-5 0 0	700	-750
Α0	Slot 1	700	-400	800	-550
	Slot 6	650	-450	800	-750
A8	Slot 1	650	-300	75 0	-400
	SLot 6	75 0	-500	800	-600
D0	Slot 1	550	-100	650	-450
	Slot 6	600	-200	700	-450
D7	Slot 1	550	-200	700	-300
	Slot 6	600	-100	700	-300